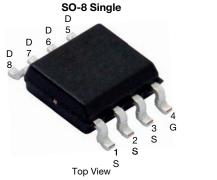
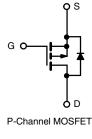


## FDS6681Z-NL-VB Datasheet P-Channel 30 V (D-S) MOSFET

PRODUCT SUMMARY				
V <sub>DS</sub> (V)	-30			
$R_{DS(on)}(\Omega)$ at $V_{GS} = 10 V$	0.0050			
$R_{DS(on)}$ ( $\Omega$ ) at $V_{GS}$ = 4.5 V	0.0080			
Q <sub>g</sub> typ. (nC)	27			
I <sub>D</sub> (A)	18			
Configuration	Single			





## **FEATURES**

- Trench Gen IV p-channel power MOSFET
- · Enables higher power density
- 100 % R<sub>g</sub> and UIS tested



### **APPLICATIONS**

- Battery management in mobile devices
- · Adapter and charger switch
- · Battery switch
- · Load switch

<b>ABSOLUTE MAXIMUM RATINGS</b> ( $T_A = 25 \text{ °C}$ , unless otherwise noted)					
PARAMETER		SYMBOL	LIMIT	UNIT	
Drain-source voltage		V <sub>DS</sub>	-30	V	
Gate-source voltage		V <sub>GS</sub>	± 20	v	
	T <sub>C</sub> = 25 °C		-18		
Continuous drain ourrent (T 150 °C)	T <sub>C</sub> = 70 °C	1	-13		
Continuous drain current (T <sub>J</sub> = 150 °C)	T <sub>A</sub> = 25 °C	I <sub>D</sub>	-11		
	T <sub>A</sub> = 70 °C	1 F	-8	Α	
Pulsed drain current (t = 100 µs)		I <sub>DM</sub>	-145	A	
Continuous source-drain diode current	T <sub>C</sub> = 25 °C	- I <sub>S</sub>	-5		
	T <sub>A</sub> = 25 °C		-2.8 <sup>b, c</sup>		
Single pulse avalanche current	urrent		-25		
Single pulse avalanche energy	L = 0.1 mH	E <sub>AS</sub>	31.2	mJ	
Maximum power dissipation	T <sub>C</sub> = 25 °C		5.6		
	T <sub>C</sub> = 70 °C	– I <sub>P</sub>	3.6	w	
	T <sub>A</sub> = 25 °C		3.1 <sup>b, c</sup>	vv	
	T <sub>A</sub> = 70 °C	1	2 <sup>b, c</sup>		
Operating junction and storage temperature range		TJ, T <sub>stg</sub>	-55 to +150	°C	
Soldering recommendations (peak temperature) <sup>c</sup>			260	U	

### THERMAL RESISTANCE RATINGS

PARAMETER	SYMBOL	TYPICAL	MAXIMUM	UNIT			
Maximum junction-to-ambient <sup>b</sup>	t ≤ 10 s	R <sub>thJA</sub>	34	40 *0			
Maximum junction-to-case (drain)	Steady state	R <sub>thJF</sub>	18	22	°C/W		

Notes

Notes
a. Package limited
b. Surface mounted on 1" x 1" FR4 board
c. t = 10 s
d. The SO-8 is a leadless package. The end of the lead terminal is exposed copper (not plated) as a result of the singulation process in manufacturing. A solder fillet at the exposed copper tip cannot be guaranteed and is not required to ensure adequate bottom side solder interconnection
a. Powerk conditions: manufacturing is not required to ensure adequate bottom side solder interconnection

Rework conditions: manual soldering with a soldering iron is not recommended for leadless components Maximum under steady state conditions is 85 °C/W e. f.

g. T<sub>C</sub> = 25 °C

<b>SPECIFICATIONS</b> (T <sub>J</sub> = 25 °C, unless otherwise noted)								
PARAMETER	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT		
Static	•			•		•		
Drain-source breakdown voltage	V <sub>DS</sub>	V <sub>GS</sub> = 0 V, I <sub>D</sub> = -250 μA	-30	-	-	V		
V <sub>DS</sub> temperature coefficient	$\Delta V_{DS}/T_{J}$	l <sub>D</sub> = -10 mA		-17	-	m)//°C		
V <sub>GS(th)</sub> temperature coefficient	$\Delta V_{GS(th)}/T_J$	I <sub>D</sub> = -250 μA	-	5.5	-	mV/°C		
Gate-source threshold voltage	V <sub>GS(th)</sub>	$V_{DS} = V_{GS}$ , $I_D = 250 \ \mu A$	-1	-	-2.2	V		
Gate-source leakage	I <sub>GSS</sub>	$V_{DS} = 0 V, V_{GS} = +16 / -20 V$	-	-	100	nA		
Zere gete veltege drein eurrent		$V_{DS} = -30 \text{ V}, \text{ V}_{GS} = 0 \text{ V}$	-	-	-1	μΑ		
Zero gate voltage drain current	I <sub>DSS</sub>	$V_{DS} = -30 \text{ V}, \text{ V}_{GS} = 0 \text{ V}, \text{ T}_{J} = 70 ^{\circ}\text{C}$	-	-	-15			
On-state drain current <sup>a</sup>	I <sub>D(on)</sub>	$V_{DS} \ge$ -10 V, $V_{GS}$ = -10 V	-40	-	-	Α		
Drein course en state registernes à	D	V <sub>GS</sub> = -10 V, I <sub>D</sub> = -15 A	-	0.0050	-	6		
Drain-source on-state resistance <sup>a</sup>	R <sub>DS(on)</sub>	$V_{GS} = -4.5 \text{ V}, \text{ I}_{D} = -10 \text{ A}$	-	0.0080	-	Ω		
Forward transconductance a	9 <sub>fs</sub>	V <sub>DS</sub> = -15 V, I <sub>D</sub> = -15 A	-	81	-	S		
Dynamic <sup>b</sup>	•		•	•	•			
Input capacitance	C <sub>iss</sub>		-	3490	-	pF		
Output capacitance	C <sub>oss</sub>	V <sub>DS</sub> = -15 V, V <sub>GS</sub> = 0 V, f = 1 MHz	-	1420	-			
Reverse transfer capacitance	C <sub>rss</sub>		-	70	-	1		
Total gate charge	Qg	$V_{DS} = -15 \text{ V}, \text{ V}_{GS} = -10 \text{ V}, \text{ I}_{D} = -10 \text{ A}$	-	56	84	nC		
			-	27	41			
Gate-source charge	Q <sub>gs</sub>	$V_{DS}$ = -15 V, $V_{GS}$ = -4.5 V, $I_{D}$ =-10 A	-	9.4	-			
Gate-drain charge	Q <sub>gd</sub>		-	8.2	-			
Gate resistance	Rg	f = 1 MHz	1.5	3.5	6	Ω		
Turn-on delay time	t <sub>d(on)</sub>		-	15	30	- ns		
Rise time	t <sub>r</sub>	V <sub>DD</sub> = -15 V, R <sub>L</sub> = 1.5 Ω, I <sub>D</sub> ≅ -10 A,	-	6	12			
Turn-off delay time	t <sub>d(off)</sub>	$V_{\text{GEN}} = -10 \text{ V}, \text{ R}_{\text{g}} = 1 \Omega$	-	39	78			
Fall time	t <sub>f</sub>		-	10	20			
Turn-on delay time	t <sub>d(on)</sub>		-	34	68			
Rise time	t <sub>r</sub>	V <sub>DD</sub> = -15 V, R <sub>L</sub> = 1.5 Ω, I <sub>D</sub> ≅ -10 A,	-	86	172			
Turn-off delay time	t <sub>d(off)</sub>	$V_{GEN}$ = -4.5 V, $R_g$ = 1 $\Omega$	-	31	62			
Fall time	t <sub>f</sub>		-	22	44			
Drain-Source Body Diode Characteristics								
Continuous source-drain diode current	IS	T <sub>C</sub> = 25 °C	-	-	-5	•		
Pulse diode forward current	I <sub>SM</sub>		-	-	-150	A		
Body diode voltage	V <sub>SD</sub>	I <sub>S</sub> = -5 A, V <sub>GS</sub> = 0 V	-	-0.73	-1.1	V		
Body diode reverse recovery time	t <sub>rr</sub>		-	44	88	ns		
Body diode reverse recovery charge	Q <sub>rr</sub>		-	41	82	nC		
Reverse recovery fall time	t <sub>a</sub>	I <sub>F</sub> = -10 A, di/dt = 100 A/μs, T <sub>J</sub> = 25 °C	-	19	-			
Reverse recovery rise time	t <sub>b</sub>		-	25	-	ns		

Notes

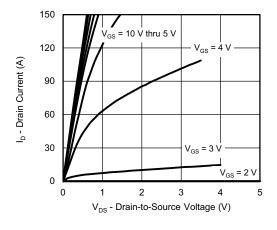
a. Pulse test; pulse width  $\leq$  300  $\mu s,$  duty cycle  $\leq$  2 %

b. Guaranteed by design, not subject to production testing

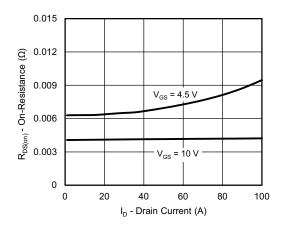
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

semi

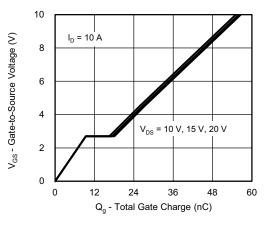




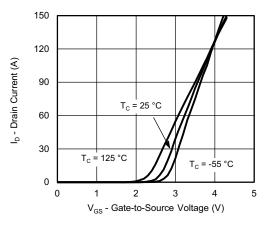
**Output Characteristics** 



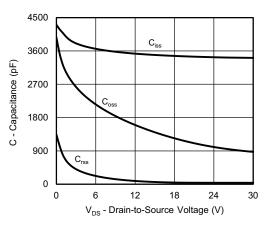
**On-Resistance vs. Drain Current and Gate Voltage** 



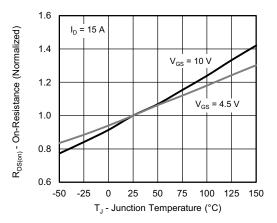
Gate Charge



**Transfer Characteristics** 

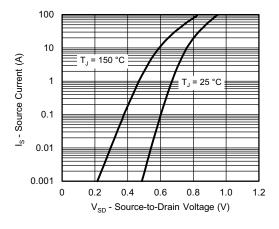


Capacitance

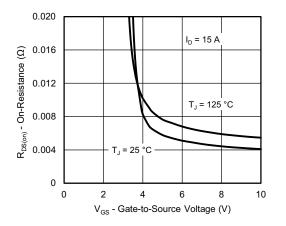


**On-Resistance vs. Junction Temperature** 

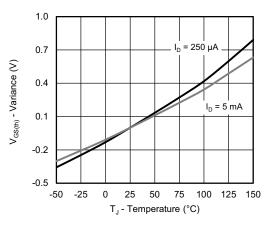




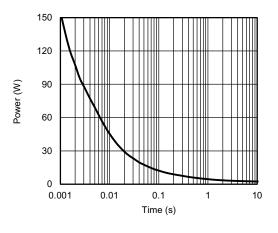
Source-Drain Diode Forward Voltage



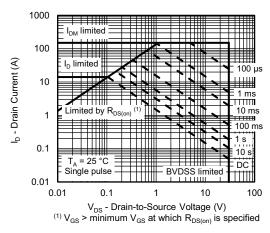
On-Resistance vs. Gate-to-Source Voltage



**Threshold Voltage** 

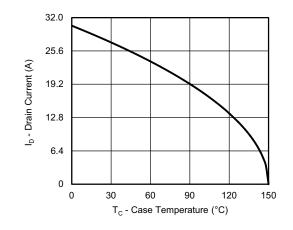


Single Pulse Power, Junction-to-Ambient

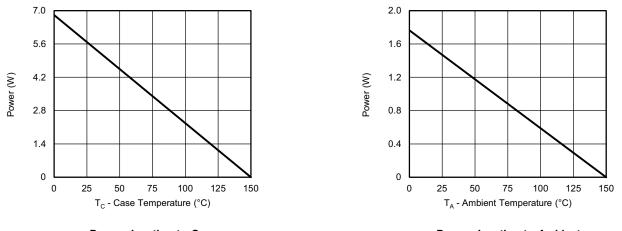


Safe Operating Area, Junction-to-Ambient





Current Derating <sup>a</sup>



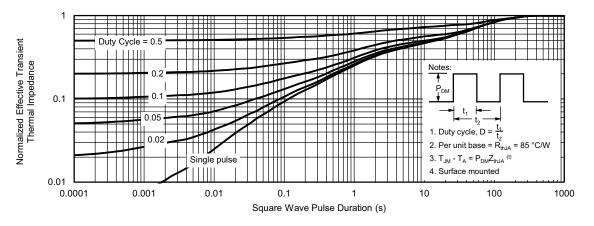
Power, Junction-to-Case

Power, Junction-to-Ambient

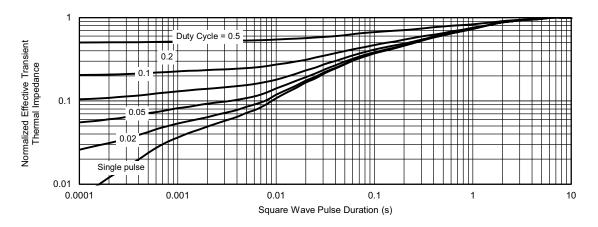
#### Note

a. The power dissipation P<sub>D</sub> is based on T<sub>J</sub> max. = 150 °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit





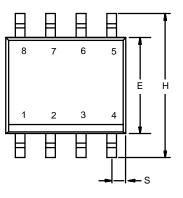
Normalized Thermal Transient Impedance, Junction-to-Ambient

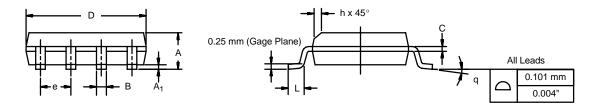


Normalized Thermal Transient Impedance, Junction-to-Case



# SOIC (NARROW): 8-LEAD JEDEC Part Number: MS-012

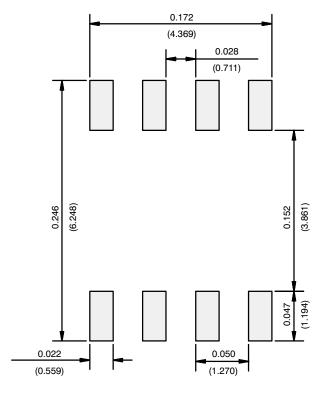




	MILLIN	IETERS	INC	HES	
DIM	Min	Max	Min	Max	
A	1.35	1.75	0.053	0.069	
A <sub>1</sub>	0.10	0.20	0.004	0.008	
В	0.35	0.51	0.014	0.020	
С	0.19	0.25	0.0075	0.010	
D	4.80	5.00	0.189	0.196	
E	3.80	4.00	0.150	0.157	
е	1.27	BSC	0.050 BSC		
Н	5.80	6.20	0.228	0.244	
h	0.25	0.50	0.010	0.020	
L	0.50	0.93	0.020	0.037	
q	0°	8°	0°	8°	
S	0.44	0.64	0.018	0.026	
ECN: C-06527-Rev. I, 11-Sep-06 DWG: 5498					



## **RECOMMENDED MINIMUM PADS FOR SO-8**



Recommended Minimum Pads Dimensions in Inches/(mm)



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